

DM74S00

Quad 2-Input NAND Gate

General Description

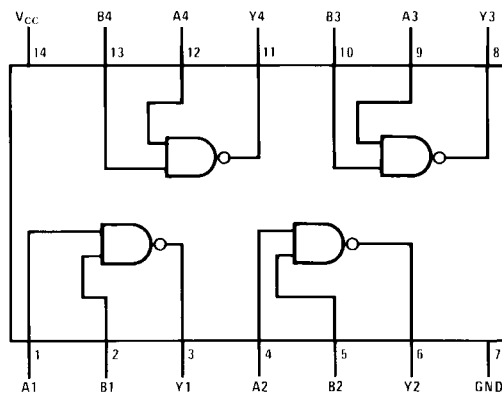
This device contains four independent gates each of which performs the logic NAND function.

Ordering Code:

Order Number	Package Number	Package Description
DM74S00M	M14A	14-Lead Small Outline Integrated Circuit (SOIC), JEDEC MS-120, 0.150 Narrow
DM74S00N	N14A	14-Lead Plastic Dual-In-Line Package (PDIP), JEDEC MS-001, 0.300 Wide

Devices also available in Tape and Reel. Specify by appending the suffix letter "X" to the ordering code.

Connection Diagram



Function Table

$$Y = \overline{AB}$$

Inputs		Output
A	B	Y
L	L	H
L	H	H
H	L	H
H	H	L

H = HIGH Logic Level
L = LOW Logic Level

Absolute Maximum Ratings(Note 1)

Supply Voltage	7V
Input Voltage	5.5V
Operating Free Air Temperature Range	0°C to +70°C
Storage Temperature Range	-65°C to +150°C

Note 1: The "Absolute Maximum Ratings" are those values beyond which the safety of the device cannot be guaranteed. The device should not be operated at these limits. The parametric values defined in the Electrical Characteristics tables are not guaranteed at the absolute maximum ratings. The "Recommended Operating Conditions" table will define the conditions for actual device operation.

Recommended Operating Conditions

Symbol	Parameter	Min	Nom	Max	Units
V _{CC}	Supply Voltage	4.75	5	5.25	V
V _{IH}	HIGH Level Input Voltage	2			V
V _{IL}	LOW Level Input Voltage			0.8	V
I _{OH}	HIGH Level Output Current			-1	mA
I _{OL}	LOW Level Output Current			20	mA
T _A	Free Air Operating Temperature	0		70	°C

Electrical Characteristics

over recommended operating free air temperature range (unless otherwise noted)

Symbol	Parameter	Conditions	Min	Typ (Note 2)	Max	Units
V _I	Input Clamp Voltage	V _{CC} = Min, I _I = -18 mA			-1.2	V
V _{OH}	HIGH Level Output Voltage	V _{CC} = Min, I _{OH} = Max V _{IL} = Max	2.7	3.4		V
V _{OL}	LOW Level Output Voltage	V _{CC} = Min, I _{OL} = Max V _{IH} = Min			0.5	V
I _I	Input Current @ Max Input Voltage	V _{CC} = Max, V _I = 5.5V			1	mA
I _{IH}	HIGH Level Input Current	V _{CC} = Max, V _I = 2.7V			50	μA
I _{IL}	LOW Level Input Current	V _{CC} = Max, V _I = 0.5V			-2	mA
I _{OS}	Short Circuit Output Current	V _{CC} = Max (Note 3)	-40		-100	mA
I _{CCH}	Supply Current with Outputs HIGH	V _{CC} = Max		10	16	mA
I _{CCL}	Supply Current with Outputs LOW	V _{CC} = Max		20	36	mA

Switching Characteristics

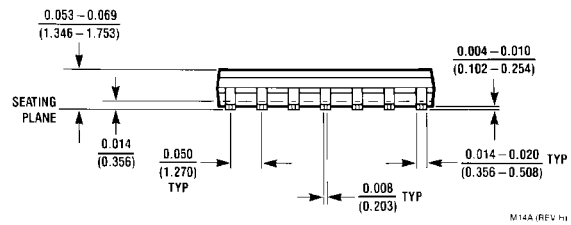
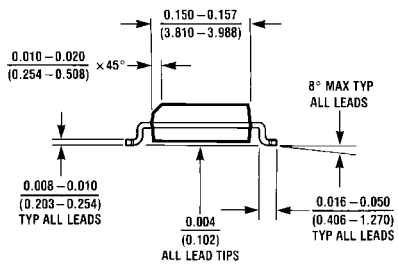
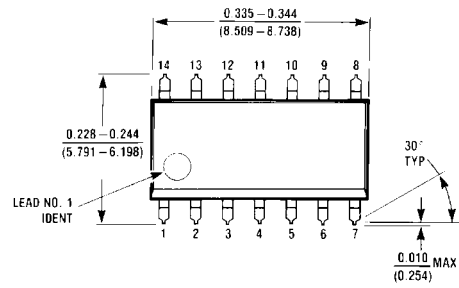
at V_{CC} = 5V and T_A = 25°C (See Section 1 for Test Waveforms and Output Load)

Symbol	Parameter	R _L = 280Ω				Units
		C _L = 15 pF		C _L = 50 pF		
		Min	Max	Min	Max	
t _{PLH}	Propagation Delay Time LOW-to-HIGH Level Output	2	4.5	2	7	ns
t _{PHL}	Propagation Delay Time HIGH-to-LOW Level Output	2	5	2	8	ns

Note 2: All typicals are at V_{CC} = 5V, T_A = 25°C.

Note 3: Not more than one output should be shorted at a time and the duration should not exceed one second.

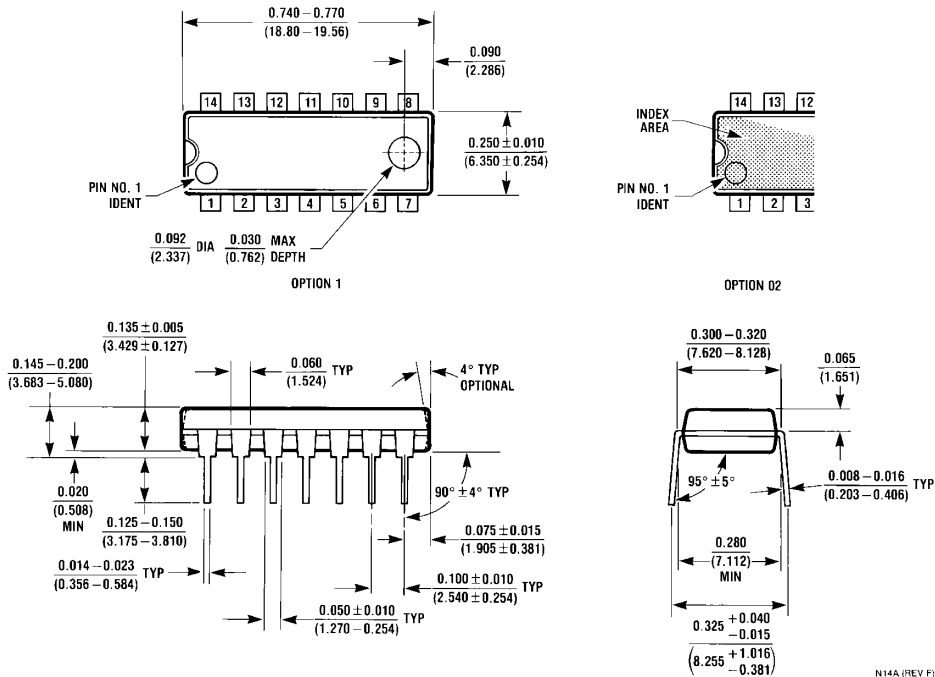
Physical Dimensions inches (millimeters) unless otherwise noted



**14-Lead Small Outline Integrated Circuit (SOIC), JEDEC MS-120, 0.150 Narrow
Package Number M14A**

M14A (REV. H)

Physical Dimensions inches (millimeters) unless otherwise noted (Continued)



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